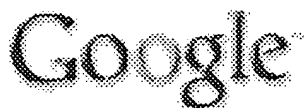


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... C. BASSO, "Spice predicts differential conducted EMI ...

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1 [EMI-noise analysis under ASIC design environment](#)



Sachio Hayashi, Masaaki Yamada

 April 1999 **Proceedings of the 1999 international symposium on Physical design**

Publisher: ACM Press

 Full text available: pdf(912.47 KB) Additional Information: [full citation](#), [references](#), [index terms](#)

2 [Simulating 3-D retarded interconnect models using complex frequency hopping \(CFH\)](#)

Eli Chiprout, Hansruedi Heeb, Michel S. Nakhla, Alber E. Ruehli

 November 1993 **Proceedings of the 1993 IEEE/ACM international conference on Computer-aided design**

Publisher: IEEE Computer Society Press

 Full text available: pdf(665.42 KB) Additional Information: [full citation](#), [references](#), [citations](#)

3 [Proceedings of the SIGNUM conference on the programming environment for development of numerical software](#)


 March 1979 **ACM SIGNUM Newsletter**, Volume 14 Issue 1

Publisher: ACM Press

 Full text available: pdf(5.02 MB) Additional Information: [full citation](#)

4 [Robust Elmore delay models suitable for full chip timing verification of a 600MHz CMOS microprocessor](#)



Nevine Nassif, Madhav P. Desai, Dale H. Hall

 May 1998 **Proceedings of the 35th annual conference on Design automation**

Publisher: ACM Press

Full text available: pdf(271.32 KB)

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In this paper we introduce a method for computing the Elmore delay of MOS circuits which relies on a model of the capacitance of MOS devices and a model of the Elmore delay of individual MOS devices. The resistance of a device is not explicitly modelled. The

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H Kitayoshi, K Sawaya - Electronics & Communications in Japan, Part 1: ..., 1999 - doi.wiley.com

... Key words: Electromagnetic holography; EMC/ **EMI measurement**; resolution; visualization range; parti- tioned **FFT**. 1. Introduction ...

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Far-field predictions from near-field measurements using an exact integral equation solution - group of 2 »

R Laroussi, GI Costache - Electromagnetic Compatibility, IEEE Transactions on, 1994 - [ieeexplore.ieee.org](#)

... is, however, more immune to aliasing error because **FFT**-based algorithms ... The radiating electronic equipment, which in the standard **EMI measurement** procedure is ...

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Improving a mode-stirred chamber utilizing acoustic diffusers

M Petirsh, A Schwab - Electromagnetic Compatibility, 1998. 1998 IEEE International ..., 1998 - [ieeexplore.ieee.org](#)

... 4]. An alternative method of **EMI** testing is ... plying a fast fourier transformation (**FFT**) the simulation ... Evaluating the simulation results the **measure** of quality ...

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NICMOS/NCS **EMI** Test Data Results - group of 2 »

LE Bergeron - NICMOS TIR, 1998 - [stsci.edu](#)

... spectra were measured per-quad by taking the **FFT** of the ... DN Actual **EMI** Test Data, zoomed ... the quads, although **measuring** the same induced signal, **measure** it phase ...

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Anticipating **EMI** from coupling between high-speed digital and I/O lines

W Cui, M Li, X Luo, JL Drowniak, TH Hubing, TP ... - ... Compatibility, 1999 IEEE International Symposium on, 1999 - [ieeexplore.ieee.org](#)

... layer PCB de- sign and result in significant **EMI**. ... calculated from the Fast Fourier llansform (**FFT**) of the ... HP8753D network analyzer was used to **measure** the (S211 ...

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Application of switched-circuit simulators in power electronicsdesign - group of 2 »

VJ Thottuvellil, FS Tsai, D Moore - Applied Power Electronics Conference and Exposition, 1993. ..., 1993 - [ieeexplore.ieee.org](#)

Page 1 0-7803-0982-0/93 \$3.00 1993 IEEE Application of Switched-Circuit Simulators in Power Electronics Design V. Joseph Thottuvellil, Fu-Sheng Tsai, D. Scott ...

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6 GHz Time Domain Measurement Of Fasttransient Events

R Wallace - Electromagnetic Compatibility, 1992. Symposium Record. IEEE ..., 1992 - [ieeexplore.ieee.org](#)

... 6 0Hz bandwidth contact (us- charge **measurement** results and ... **FFT** of 2kV Contact Discharge I Air Discharge ... bandwidth to fully characterize the **EMI** generated by ...

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1 [A New Design Flow and Testability Measure for the Generation of a Structural Test and BIST for Analogue and Mixed-Signal Circuits](#)

C. Hoffmann

 March 2002 **Proceedings of the conference on Design, automation and test in Europe**

Publisher: IEEE Computer Society

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For the generation of defect-oriented tests a system is de-velopedthat includes the synthesis of self-test structures.With the objective to generate a highly efficient analoguetest, the fault simulation methods are greatly enhanced: (1)A new testability measure, (2)the possibility to distinguishbetween not-to-detect and hard-to-detect faults with respectto the tolerances of the respective measurement system. Byrepresenting a new design flow and using the fault simulationin a very early design stag ...

2 [Automatic Test Generation for Maximal Diagnosis of Linear Analogue Circuits](#)

Salvador Mir, Bernard Courtois, Marcelo Lubaszewski, Vladimir Kolarik

 March 1996 **Proceedings of the 1996 European conference on Design and Test**

Publisher: IEEE Computer Society

 Full text available: [pdf\(603.97 KB\)](#)

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A fault-based multifrequency test generation and fault diagnosis procedure is proposed in this work. The procedure selects a minimal set of test measures and generates the minimal set of frequency tests which guarantee maximum fault coverage and maximal diagnosis of circuit AC hard/soft faults. The procedure is exemplified for several self-testable linear analogue circuits for which the test measures that may be used are a priori known.

Keywords: analogue ATPG, fault-based testing, analogue BIST, fault diagnosis.

3 [Partial scan design based on circuit state information](#)



Dong Xiang, Srikanth Venkataraman, W. Kent Fuchs, Janak H. Patel

 June 1996 **Proceedings of the 33rd annual conference on Design automation**

Publisher: ACM Press

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- 1 [Energy delay measures of barrel switch architectures for pre-alignment of floating point operands for addition](#)



R. V. K. Pillai, D. Al-Khalili, A. J. Al-Khalili

 August 1997 **Proceedings of the 1997 international symposium on Low power electronics and design**

Publisher: ACM Press

 Full text available: [pdf\(572.02 KB\)](#) Additional Information: [full citation](#), [references](#), [citations](#)

- 2 [Low power and EMI high frequency crystal oscillator](#)



Rafael Fried, Reuven Holzer

 April 1995 **Proceedings of the 1995 international symposium on Low power design**

Publisher: ACM Press

 Full text available: [pdf\(107.90 KB\)](#) Additional Information: [full citation](#), [references](#), [citations](#), [index terms](#)

- 3 [Analog and Digital Circuit Design in 65 nm CMOS: End of the Road?](#)

Georges Gielen, Wim Dehaene, Phillip Christie, Dieter Draxelmayr, Edmond Janssens, Karen Maex, Ted Vucurevich

 March 2005 **Proceedings of the conference on Design, Automation and Test in Europe - Volume 1**

Publisher: IEEE Computer Society

 Full text available: [pdf\(360.09 KB\)](#) Additional Information: [full citation](#), [abstract](#)

This special session addresses the problems that designers face when implementing analog and digital circuits in nanometer technologies. An introductory embedded tutorial will give an overview of the design problems at hand : the leakage power and process variability and their implications for digital circuits and memories, and the reducing supply voltages, the design productivity and signal integrity problems for embedded analog blocks. Next, a panel of experts from both industrial semiconductor h ...

- 4 [Advances in synthesis: Design of asynchronous circuits by synchronous CAD tools](#)



Alex Kondratyev, Kelvin Lwin

 June 2002 **Proceedings of the 39th conference on Design automation**

Publisher: ACM Press

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IEEE JNL IEEE Journal or Magazine

IEEE JNL IEE Journal or Magazine

IEEE CNF IEEE Conference Proceeding

IEEE CNF IEE Conference Proceeding

IEEE STD IEEE Standard

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- ☐ **1. Variable Impedance in Measuring EMI Filter's Insertion Loss**
 Drinovsky, J.; Svacina, J.; Zamazal, M.; Urbanec, T.; Lacik, J.;
[Communications, 2005 Asia-Pacific Conference on](#)
 03-05 Oct. 2005 Page(s):24 - 27
[AbstractPlus](#) | Full Text: [PDF\(392 KB\)](#) IEEE CNF
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- ☐ **2. A method to measure EMI due to electric field coupling on PCB**
 Pong, B.M.H.; Lee, A.C.M.;
[Power Conversion Conference - Nagaoka 1997., Proceedings of the](#)
 Volume 2, 3-6 Aug. 1997 Page(s):1007 - 1012 vol.2
 Digital Object Identifier 10.1109/PCCON.1997.638393
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- 1 [Signal processing: A wavelet-based approach for frequency estimation of interference signals in printed circuit boards](#)
 A. Kacha, F. Grenez, P. De Doncker, K. Benmahammed
 September 2003 **Proceedings of the 1st international symposium on Information and communication technologies ISICT '03**

Publisher: Trinity College Dublin

 Full text available: pdf(312.44 KB) Additional Information: [full citation](#), [abstract](#), [references](#)

This paper proposes a wavelet-based approach for frequency estimation of the source of interference in a PCB. The frequency constitutes a relevant information that characterizes the disturbance signal and may lead to the identification of its source. The estimation procedure is only based on the disturbed signal, already available, from which the interference signal is reconstructed by performing a wavelet decomposition at level one. The estimated interference is then appropriately processed to ...

- 2 [Design support of printed circuit boards concerning radiation and irradiation effects \(EMI\): using an extended EMC-Workbench](#)
 Stefan Öing, Werner John
 September 1994 **Proceedings of the conference on European design automation**

Publisher: IEEE Computer Society Press

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- 3 [Frequency domain microwave modeling using retarded partial element equivalent circuits](#)



Hansruedi Heeb, Saila Ponnappalli, Albert E. Ruehli

 July 1993 **Proceedings of the 30th international conference on Design automation**

Publisher: ACM Press

 Full text available: pdf(411.23 KB) Additional Information: [full citation](#), [references](#), [citations](#), [index terms](#)

- 4 [Wireless session: information design methodology: Design methodology for wireless nodes with printed antennas](#)



Jean-Samuel Chenard, Chun Yiu Chu, Željko Žilić, Milica Popović

 June 2005 **Proceedings of the 42nd annual conference on Design automation**